SCLS151B - DECEMBER 1982 - REVISED MAY 1997

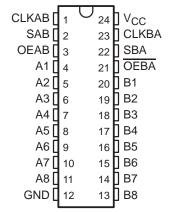
- Independent Registers and Enables for A and B Buses
- Multiplexed Real-Time and Stored Data
- True Data Paths
- High-Current 3-State Outputs Can Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT)
 300-mil DIPs

description

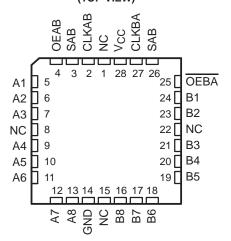
These devices consist of bus-transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output-enable (OEAB and OEBA) inputs are provided to control the transceiver functions. Select-control (SAB and SBA) inputs are provided to select real-time or stored data transfer. A low input level selects real-time data, and a high input level selects stored data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the 'HC652.

Data on the A or B data bus, or both, can be stored in the internal D-type flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) terminals regardless of the select- or output-control terminals. When SAB and SBA are in the real-time transfer mode, it is possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and OEBA. In this configuration, each output reinforces its input. When all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.

SN54HC652...JT OR W PACKAGE SN74HC652...DW OR NT PACKAGE (TOP VIEW)



SN54HC652 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

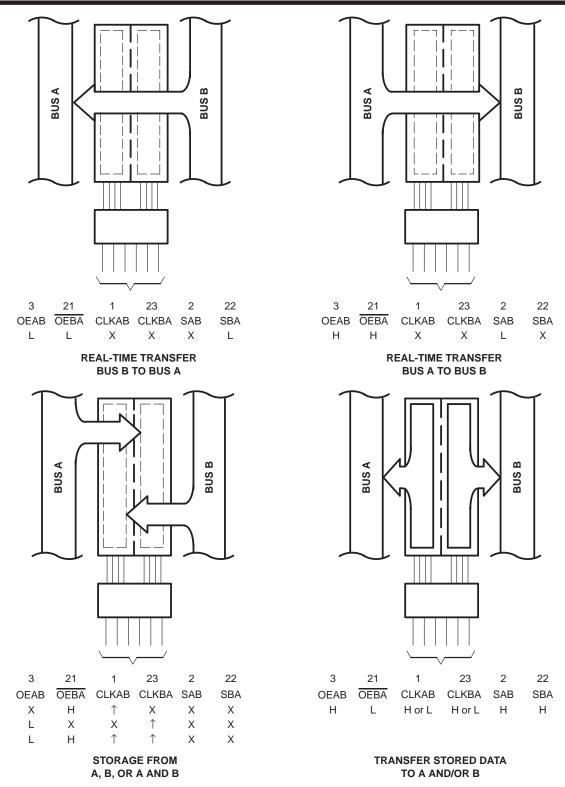
The SN54HC652 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74HC652 is characterized for operation from -40° C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



SCLS151B - DECEMBER 1982 - REVISED MAY 1997



Pin numbers shown are for the DW, JT, NT, and W packages.

Figure 1. Bus-Management Functions



SCLS151B - DECEMBER 1982 - REVISED MAY 1997

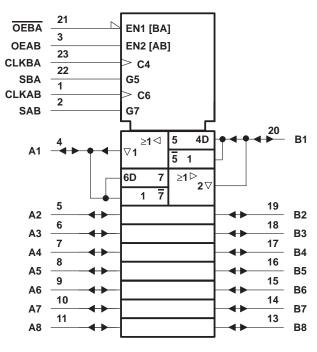
FUNCTION TABLE

		INPU	UTS DATA I/O [†]			1/0†	OPERATION OR FUNCTION	
OEAB	OEBA	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
L	Н	H or L	H or L	Х	Х	Input	Input	Isolation
L	Н	\uparrow	\uparrow	X	Χ	Input	Input	Store A and B data
Х	Н	1	H or L	Х	Х	Input	Unspecified [‡]	Store A, hold B
Н	Н	1	1	X‡	X	Input	Output	Store A in both registers
L	Х	H or L	1	Х	Х	Unspecified [‡]	Input	Hold A, store B
L	L	1	1	Х	χ‡	Output	Input	Store B in both registers
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored B data to A bus
Н	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus
Н	Н	H or L	Χ	Н	Х	Input	Output	Stored A data to B bus
Н	L	H or L	H or L	Н	Н	Output	Output	Stored A data to B bus and stored B data to A bus

[†] The data-output functions are enabled or disabled by a variety of level combinations at OEAB or OEBA. Data-input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition on the clock inputs.

Select control = H; clocks must be staggered to load both registers.

logic symbol§



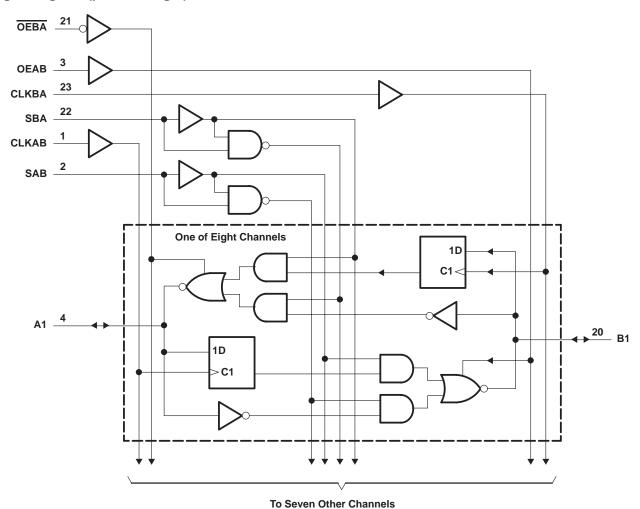
 \S This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, NT, and W packages.



[‡] Select control = L; clocks can occur simultaneously.

SCLS151B - DECEMBER 1982 - REVISED MAY 1997

logic diagram (positive logic)



Pin numbers shown are for the DW, JT, NT, and W packages.

absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	81°C/W
NT package	67°C/W
Storage temperature range, T _{sto}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

SCLS151B - DECEMBER 1982 - REVISED MAY 1997

recommended operating conditions

			SN	SN54HC652		SN	174HC65	2	LINUT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15		7	3.15			V
		V _{CC} = 6 V	4.2		< l	4.2			
		V _{CC} = 2 V	0	ZEL	0.5	0		0.5	
V_{IL}	Low-level input voltage	V _{CC} = 4.5 V	0	2	1.35	0		1.35	V
		VCC = 6 V	0	Ç,	1.8	0		1.8	
٧ _I	Input voltage		0	2	VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
TA	Operating free-air temperature	_	-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAD	AMETER	TEST CO	MOITIONS	Vaa	Т	A = 25°C	;	SN54H	IC652	SN74HC652		UNIT
PAR	AIVIETER	TEST CONDITIONS		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
				2 V	1.9	1.998		1.9		1.9		
			I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Vон		$V_I = V_{IH}$ or V_{IL}		6 V	5.9	5.999		5.9		5.9		V
			$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
			$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2	Th.	5.34		
		VI = VIH or VIL		2 V		0.002	0.1		0.1		0.1	
			I _{OL} = 20 μA	4.5 V		0.001	0.1	4	0.1		0.1	
VOL				6 V		0.001	0.1	40	0.1		0.1	V
			I _{OL} = 6 mA	4.5 V		0.17	0.26	20	0.4		0.33	
			I _{OL} = 7.8 mA	6 V		0.15	0.26	O _W	0.4		0.33	
Ц	Control inputs	VI = VCC or 0		6 V		±0.1	±100	7	±1000		±1000	nA
loz	A or B	VO = VCC or GN	D	6 V		±0.01	±0.5		±10		±5	μΑ
Icc		$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ
Ci	Control inputs			2 V to 6 V		3	10		10		10	pF

SCLS151B - DECEMBER 1982 - REVISED MAY 1997

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		Vaa	T _A = :	25°C	SN54H	IC652	SN74H	IC652	UNIT
		vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	0	6	0	4.3	0	5.5	
fclock	Clock frequency	4.5 V	0	31	0	22	0	27	MHz
		6 V	0	36	0	25	0	31	
		2 V	80		115	'VIR	95		
t _W	Pulse duration, CLKBA or CLKAB high or low	4.5 V	16		23	PE	19		ns
			14		20		16		
		2 V	100		150		125		
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	4.5 V	20		30		25		ns
		6 V	17		26		21		
	Hold time, A after CLKAB↑ or B after CLKBA↑	2 V	5		5		5	·	ns
th		4.5 V	5		5		5		
			5		5		5		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 2)

DADAMETED	FROM	то	V	T,	λ = 25°C	;	SN54F	IC652	SN74F	IC652	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	6	10		4.3		5.5		
fmax			4.5 V	31	40		22		27		MHz
			6 V	36	45		25		31		
			2 V		65	180		270		225	
	CLKBA or CLKAB	A or B	4.5 V		18	36		54		45	
			6 V		14	31		46		38	
			2 V		50	135		205		170	
^t pd	A or B	B or A	4.5 V		14	27		41		34	ns
			6 V		11	23		35		29	
	SBA or SAB†	A or B	2 V		70	190	4	285		240	
			4.5 V		20	38	32	57		48	
			6 V		16	32	702	48		41	
			2 V		85	245	Q	370		305	
t _{en}	OEBA or OEAB	A or B	4.5 V		25	49		74		61	ns
			6 V		20	42		63		52	
			2 V		50	245		370		305	
^t dis	OEBA or OEAB	A or B	4.5 V		23	49		74		61	ns
			6 V		20	42		63		52	
			2 V		28	60		90		75	
t _t		Any	4.5 V		8	12		18		15	ns
			6 V		6	10		15		13	

[†] These parameters are measured with the internal output state of the storage register opposite that of the bus input.



SCLS151B - DECEMBER 1982 - REVISED MAY 1997

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 2)

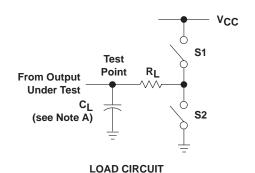
PARAMETER	FROM	то	Vaa	T,	Վ = 25 °C	;	SN54H	HC652	SN74H	C652	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V		90	265		400		330		
	CLKBA or CLKAB	A or B	4.5 V		24	53		80		66		
			6 V		18	46		68		57		
			2 V		70	220		335		275		
t _{pd}	A or B	B or A	4.5 V		20	44		70		55	ns	
			6 V		15	38		57		48		
			2 V		80	275	6	415		345		
	SBA or SAB†	A or B	4.5 V		24	55	20	83		69	•	
			6 V		20	47	0%	70		60		
			2 V		100	330	Q	500		410		
t _{en}	OEBA or OEAB	A or B	4.5 V		33	66		100		82	ns	
			6 V		27	57		85		71		
		_	2 V		45	210		315		265		
t _t		Any	4.5 V		17	42		63		53	ns	
			6 V		13	36		53		43		

[†] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

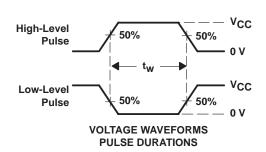
operating characteristics, T_A = 25°C

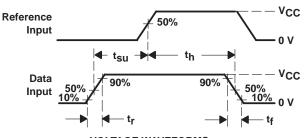
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load	50	pF

PARAMETER MEASUREMENT INFORMATION

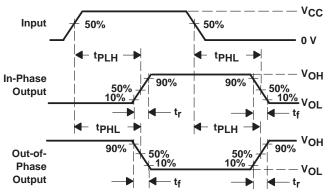


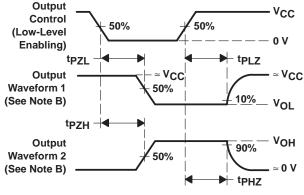
PARAI	WETER	RL	R _L C _L		S2	
	t _{PZH} 50 pF		Open	Closed		
ten	tPZL	1 kΩ or 150 pF		Closed	Open	
4 11.	tPHZ	1 k Ω	50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pi	Closed	Open	
t _{pd} or	t _t	50 pF — or 150 pF		Open	Open	





VOLTAGE WAVEFORMS SETUP AND HOLD AND INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6$ ns, $t_f = 6$ ns.
- D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLz and tpHz are the same as t_{dis}.
- G. tpzL and tpzH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated